PCN Number:		20	20150116000A PCN Date: 01/30/2015							015				
Title:	Qualification						_				Devices	in PD	)IP Packa	је
Custome	er Contact:	PCN	l Ma	nager		Dept:	Qua	lity Ser	vice	es				
Propose	d 1 <sup>st</sup> Ship Da	ite:	0	4/19	/2015	Esti	mated	Samp	le A	Availa	bility:		/ided upo uest	n
Change	Change Type:													
	mbly Site				embly F				$\square$		embly M			
Desi			Щ		trical S				Щ		hanical S		fication	
Test							pping/Labeling				Test Process			
	er Bump Site		Wafer Bump Wafer Fab M			•			<u> </u>		er Bump			
ware	er Fab Site		<u> </u>							Wafer Fab Process				
				Part	numbe									
December	ion of Chana					PCN D	etaii	<u> </u>						
Descript	ion of Chang	je:												
comparis Texas Ins Assembly	Revision A is to update the description of change to provide clarification on the included BOM comparison table seen below. These additions are highlighted and <b>bolded</b> below.  Texas Instruments is pleased to announce the qualification of JCET ChuZhou as an alternate Assembly site for the PDIP devices listed below. Material differences between the current sites and new site is shown below:													
	MLA			A	LP		FMX		T		JCETCZ			
Package	14 pin PDIP 1	6 pin PD 4042500	-	pin PDIP	14 pin PDIP	8 pin PDIP 4147858	14 pin PDIP	16 pin PDIP	_	pin PDIP	14 pin PD		16 pin PDIP	
Mount Compoun Mold Compound		4042503		147858 1002027	4147858 141002027	4042503	4147858 4042503	4147858 4042503	131	204001701 102026801	13102026	801 13	204001701	
Lead Finish	NiPdAu	NiPdAu		NiPdAu	NiPdAu	NiPdAu	NiPdAu	NiPdAu		<del>Post Plate</del> Matte Sn	Post Plate Matte Si		Post Plate Matte Sn	
Bond wire compo		CU 0.96 MII		Au 1.0 MIL	Au 0.8 MIL	0.96 MIL	0.96 MIL	O.96 MIL		Cu 1.0 MIL	Cu 1.0 MIL		Cu 1.0 MIL	
								0.001						
Upon expiry of this PCN TI will combine lead free solutions in a single standard part number, for example; CD4052BE - can ship with both Matte Sn and NiPdAu/Ag.  Example:  - Customer order for 7500units of CD4052BE with 2500 units SPQ (Standard Pack Quantity per Reel).  - TI can satisfy the above order in one of the following ways.  I. 3 Reels of NiPdAu finish.  II. 3 Reels of Matte Sn finish  III. 2 Reels of Matte Sn and 1 reel of NiPdAu finish.  IV. 2 Reels of NiPdAu and 1 reel of Matte Sn finish.					<mark>ard</mark>									
Reason	for Change:													
	y of Supply													
Anticipa	ted impact o	n Fi	it, F	orm	, Funct	tion, Q	uality	or Rel	iab	ility (	positive	e / n	egative):	
None							,						•	
Changes	Changes to product identification resulting from this PCN:													

Assembly Site		
TI Malaysia	Assembly Site Origin (22L)	ASO: MLA
<u> </u>		

Microchip Technology	Assembly Site Origin (22L)	ASO: ALP
TI Mexico	Assembly Site Origin (22L)	ASO: MEX
JCET Chuzhou	Assembly Site Origin (22L)	ASO: GP6

Sample product shipping label (not actual product label)



MSL 2 /260C/1 YEAR SEAL DT 03/29/04 OPT: 1TEM: 39 LBL: 5A (L)T0:1750

(1P) \$N74L\$07N\$R (Q) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483\$I2 (P) (2P) REV: (V) 0033317 (2DL) C\$0: SHE (21L) CCO: USA (22L) A\$0: MLA (23L) ACO: MYS

# **Topside Device marking:**

Assembly site code for MLA= K
Assembly site code for ALP= 8
Assembly site code for MEX= M
Assembly site code for GP6= F

CD4052BE	LM2902N	LM393AP	SN74HC04N
CD4066BE	LM2904P	NA555P	SN74HC138N
CD4541BE	LM293P	NE5532P	SN74HC14N
LM239N	LM324NE3	OP07CP	SN74HC165N
LM258AP	LM339AN	SN74HC00N	SN74HC595N
LM258P	LM358AP	SN74HC02N	ULN2003AIN

#### **Qualification Report**

# JCET <u>Chuzhou</u> 8-pin PDIP (P) Cu Wire Package Qual Approved on 03/11/2014

#### **Product Attributes**

Attributes	Qual Device: LM358P	Qual Device: LM393P	Qual Device: NE555P	QBS Package: CD4051BE	QBS Package: ULN2003AN
Assembly Site	JCET CHUZHOU	JCET CHUZHOU	JCET CHUZHOU	JCET CHUZHOU	JCET CHUZHOU
Package Family	PDIP	PDIP	PDIP	PDIP	PDIP
Flammability Rating	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0
Wafer Fab Site	SFAB	SFAB	SFAB	SFAB	SFAB
Wafer Fab Process	JI1	JI1	JI1	HC-C	JI1

Qualification Results
Data Displayed as: Number of lots / Total sample size / Total failed

	bata bisplayed as trained of total sample size i formation						
Туре	Test Name / Condition	Duration	Qual Device: LM358P	Qual Device: LM393P	Qual Device: NE555P	QBS Package: CD4051BE	QBS Package: ULN2003AN
HAST	Biased HAST, 130C/85%RH	96 Hours	3/231/0	-	-	3/231/0	3/231/0
AC	Autoclave, 121C	96 Hours	1/77/0	-	-	3/231/0	-
TC	Temperature Cycle, -65C/150C	500 Cycles	1/77/0	-	-	3/231/0	-
HTSL	High Temp. Storage Bake, 1700	420 Hours	1/77/0	-	-	3/231/0	-
HTOL	Life Test, 150C	300 Hours	1/77/0	-	-	3/231/0	-
WBS	Ball Bond Shear	Wires	3/228/0	1/76/0	1/76/0	3/228/0	3/228/0
WBP	Bond Pull	Wires	3/228/0	1/76/0	1/76/0	3/228/0	3/228/0
SD	Solderability	8 Hours Steam Age-Pb Free	3/66/0	-	-	3/66/0	-
PD	Physical Dimensions	-	3/15/0	-	-	3/15/0	-
LI	Lead Fatigue	Leads	3/66/0	-	-	3/66/0	-
ED	Electrical Characterization	Per Datasheet Parameters	Pass	-	-	Pass	-
LI	Lead Pull to Destruction	Leads	3/66/0	-	-	3/66/0	-
FLAM	Flammability (IEC 695-2-2)	-	3/15/0	-	-	3/15/0	-
FLAM	Flammability (UL 94V-0)	-	3/15/0	-	-	3/15/0	-
FLAM	Flammability (UL-1694)	-	3/15/0	-	-	3/15/0	-

<sup>-</sup> Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
   The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
   The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles

Green/Pb-free Status: Qualified Pb-Free(SMT) and Green

TI Qualification ID: 20130204-77481

### Qualification Report

#### JCET Chuzhou 14-pin PDIP (N) Cu Wire Package Qual Approved on 02/04/2014

#### **Product Attributes**

Attributes	Qual Device: LM324N	Qual Device: LM339N	Qual Device: SN74HC164N	QBS Package: CD4051BE	QBS Package: ULN2003AN
Assembly Site	JCET CHUZHOU	JCET CHUZHOU	JCET CHUZHOU	JCET CHUZHOU	JCET CHUZHOU
Package Family	PDIP	PDIP	PDIP	PDIP	PDIP
Flammability Rating	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0
Wafer Fab Site	SFAB	SFAB	SFAB	SFAB	SFAB
Wafer Fab Process	JI1	JI1	HCMOS	HC-C	JI1
	JIT		HCMOS	HC-C	JI1

Qual Devices qualified at LEVEL1-260C: LM324N, LM339N
 Qual Device SN74HC164N is qualified at Not Classified

# - QBS: Qual By Similarity

# Qualification Results Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: LM324N	Qual Device: LM339N	Qual Device: SN74HC164N	QBS Package: CD4051BE	QBS Package: ULN2003AN
HAST	Biased HAST, 130C/85%RH	96 Hours	-	-	1/77/0	3/231/0	3/231/0
AC	Autoclave 121C	96 Hours	-	-	1/77/0	3/231/0	-
TC	Temperature Cycle -65C/150C	500 Cycles	-	-	1/77/0	3/231/0	-
HTSL	High Temp. Storage Bake 170C	420 Hours	-	-	-	3/231/0	-
HTOL	Life Test, 150C	300 Hours	-	-	1/77/0	3/231/0	-
WBS	Ball Bond Shear	Wires	3/228/0	3/228/0	3/228/0	3/228/0	3/228/0
WBP	Bond Pull	Wires	3/228/0	3/228/0	3/228/0	3/228/0	3/228/0
SD	Solderability	Pb Free/Solder	-	-	3/66/0	3/66/0	-
PD	Physical Dimensions		-	-	3/15/0	3/15/0	-
LI	Lead Fatigue		3/66/0	3/66/0	3/66/0	3/66/0	-
LI	Lead Pull to Destruction	Leads	3/66/0	3/66/0	3/66/0	3/66/0	-
FLAM	Flammability (IEC 695-2-2)		-	-	-	3/15/0	-
FLAM	Flammability (UL 94V-0)		-	-	-	3/15/0	-
FLAM	Flammability (UL-1694)		-	-	-	3/15/0	-

<sup>-</sup> Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

<sup>-</sup> QBS: Qual By Similarity - Qual Devices qualified at LEVEL1-260C: LM358P, LM393P, NE555P

<sup>-</sup> The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1khrs, 140C/480hrs, 150C/300hrs, and 155C/240hrs
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1khrs, and 170C/420hrs
- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700cyc and -65C/150C/500cyc
Quality and Environmental data is available at Ti's external Web site: http://www.ti.com/
Green/Pb-free Status:
Qualificed Pb-Free(SMT) and Green

## **Qualification Report**

#### JCET Chuzhou 16-pin PDIP (N) Cu Wire Package Qual Approved on 02/04/2014

#### **Product Attributes**

Attributes	Qual Device: CD4051BE	Qual Device: ULN2003AN
Assembly Site	JCET CHUZHOU	JCET CHUZHOU
Package Family	PDIP	PDIP
Flammability Rating	UL 94 V-0	UL 94 V-0
Wafer Fab Site	SFAB	SFAB
Wafer Fab Process	HC-C	JI1
- Qual Devices qualified at Not Classifie	- QBS: Qual By Similarity	

#### **Qualification Results**

Data Displayed as: Number of lots/Total sample size/Total failed

+	Data Displayed as: Number of lots / Total sample size / Total failed					
Туре	Test Name / Condition	Duration	Qual Device: CD4051BE	Qual Device: ULN2003AN		
HAST	Biased HAST, 130C/85%RH	96 Hours	3/231/0	3/231/0		
AC	Autoclave 121C	96 Hours	3/231/0	-		
TC	Temperature Cycle -65C/150C	500 Cycles	3/231/0	-		
HTSL	High Temp. Storage Bake, 170C	420 Hours	3/231/0	-		
HTOL	Life Test, 150C	300 Hours	3/231/0	-		
WBS	Ball Bond Shear	Wires	3/228/0	3/228/0		
WBP	Bond Pull	Wires	3/228/0	3/228/0		
SD	Solderability	8 Hours Steam Age	3/66/0	-		
PD	Physical Dimensions		3/15/0	-		
LI	Lead Fatigue	Leads	3/66/0	-		
LI	Lead Pull to Destruction	Leads	3/66/0	-		
ED	Electrical Characterization	Per Datasheet Parameters	1/77/0	-		
FLAM	Flammability (IEC 695-2-2)		3/15/0	-		
FLAM	Flammability (UL 94V-0)		3/15/0	-		
FLAM	Flammability (UL-1694)		3/15/0	-		

<sup>-</sup> Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1khrs, 140C/480hrs, 150C/300hrs, and 155C/240hrs
   The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1khrs, and 170C/420hrs
   The following are equivalent Temp Cycle options per JESD47: -55C/125C/700cyc and -65C/150C/500cyc
  Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

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USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
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Japan	PCNJapanContact@list.ti.com